



Labsphere

advancing the technology of light

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MEASURE
any light source



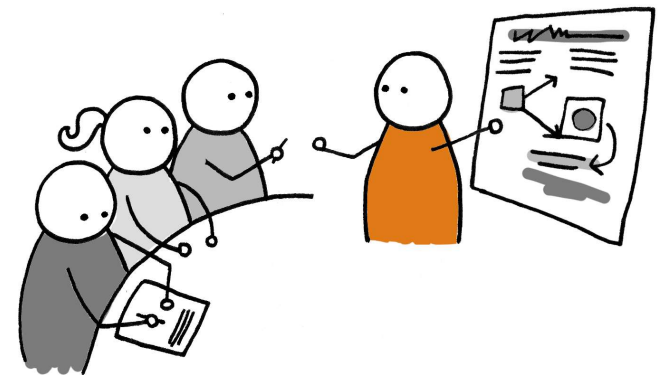
CREATE
any spectrum



REFLECT
any wavelength

MEASURE

- Agenda
 - Spheres vs. Classic Laser Measurement Solutions
 - Temporal Issues with Spheres
 - Advantages/Disadvantages
 - Calibrating Spheres for Laser Power Measurements
 - Substitution Correction
- And...if there is time...
 - Spheres throughput with various devices
 - Laser Damage Thresholds
- (Not Covered) Product Slides & Supporting Information



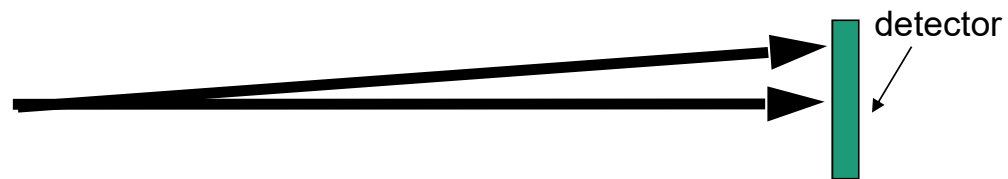
Classic Laser Power Meter



SM1-Threaded Adapter
for the PM160T



Classic Laser Power Meter



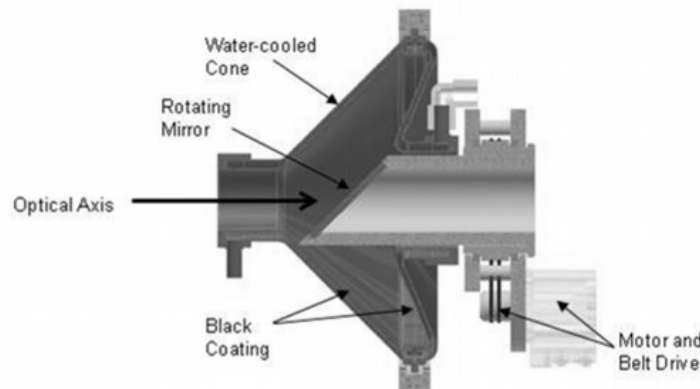
Thermopile, Absorber Cavities & Pyroelectric

PROS

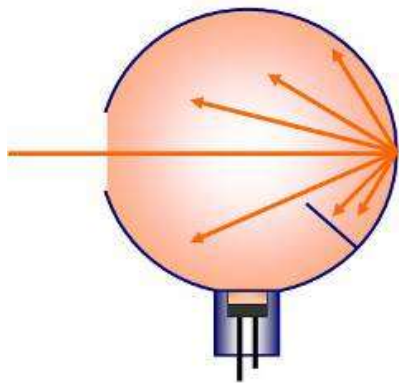
- Convert optical to thermal
- Can Very Accurate
- High damage thresholds
- Pyros can be very fast

CONS

- Thermos can be very slow
- Drift / Sensitive to Ambient changes
- Single wavelength at a time
- Can be angularly/spatially sensitive



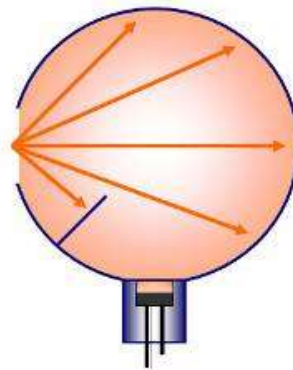
Spheres - Differentiating Collection Geometry



collimated beams

attenuation >
1000:1

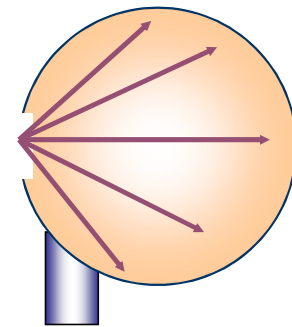
baffle the
"hotspot"



divergent, non-symmetrical beams

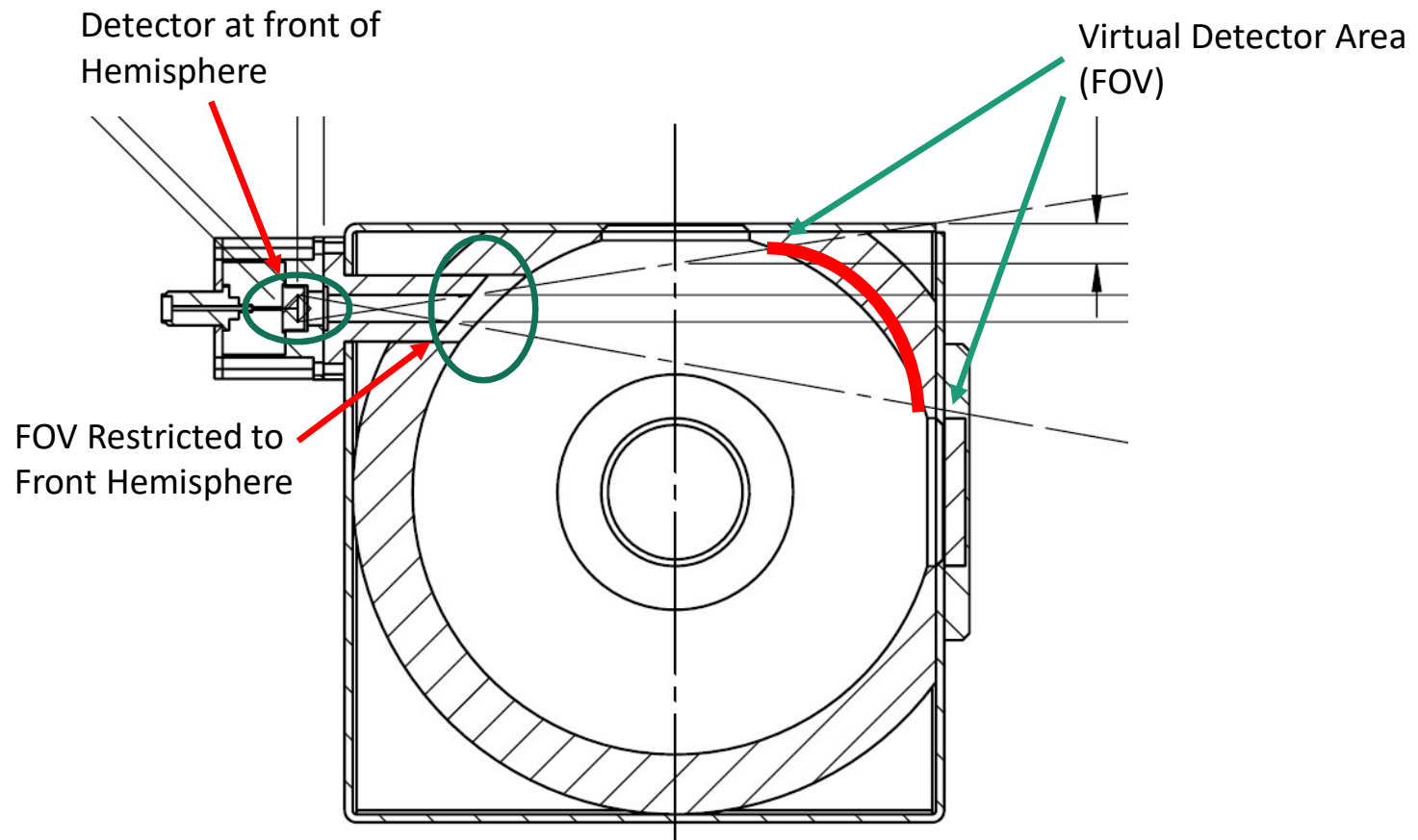
attenuation > 1000:1
total integration

FOV cannot overlap
irradiation

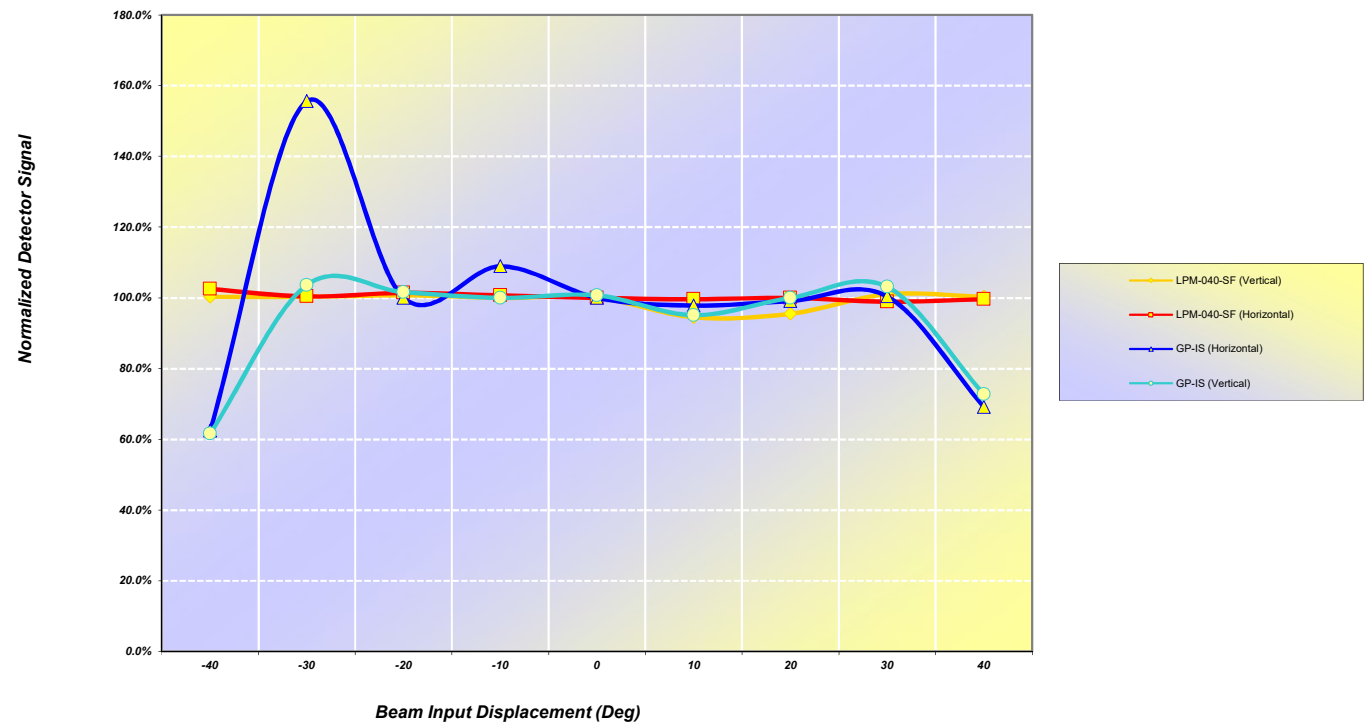
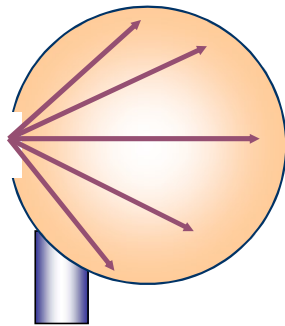


attenuation >
10000:1

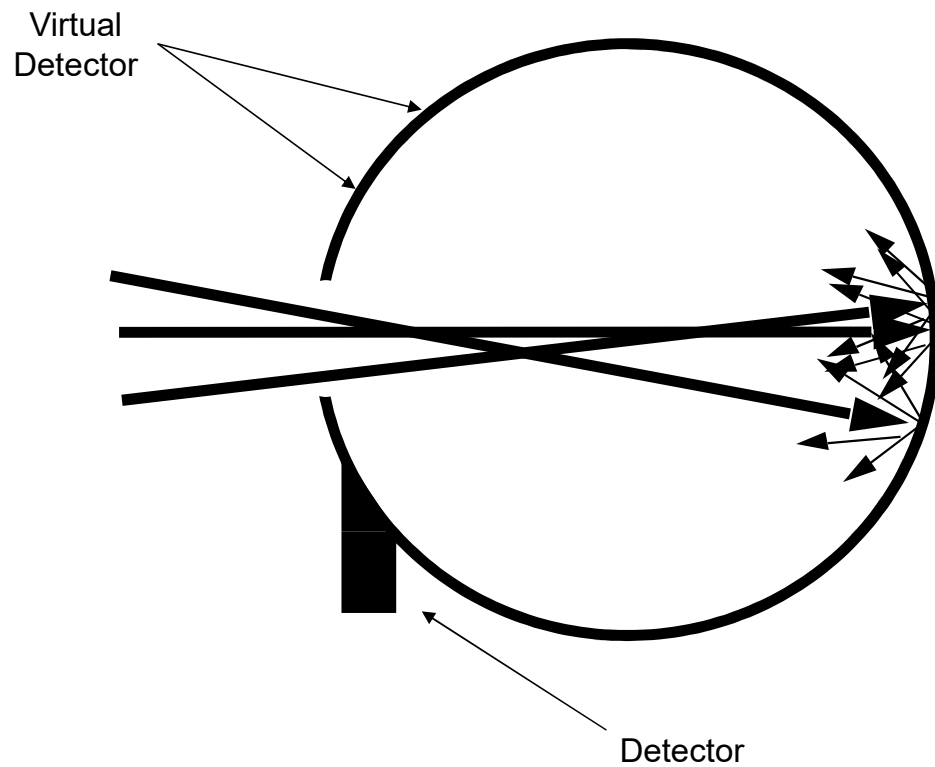
Cut Away of Off-Axis Sphere Design



Angular Sensitivity of Off-Axis Design



Sphere Laser Power Meter



Protected Aluminum
0.1-0.3um



Spectralon (PTFE)
0.2-2.5um (even
3.0um)



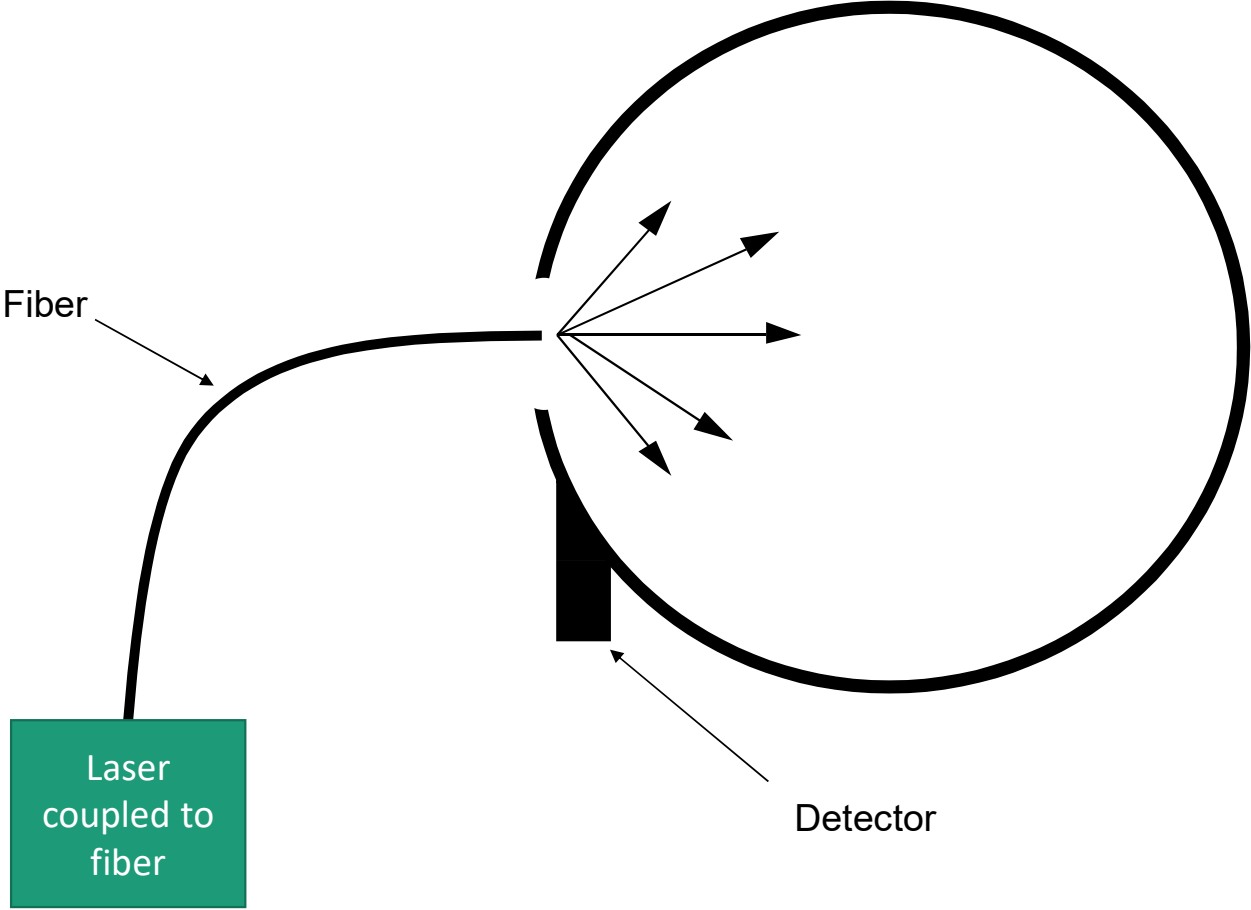
Spectrafect (BaSO4)
0.4-1.3um (out to
2.5um).



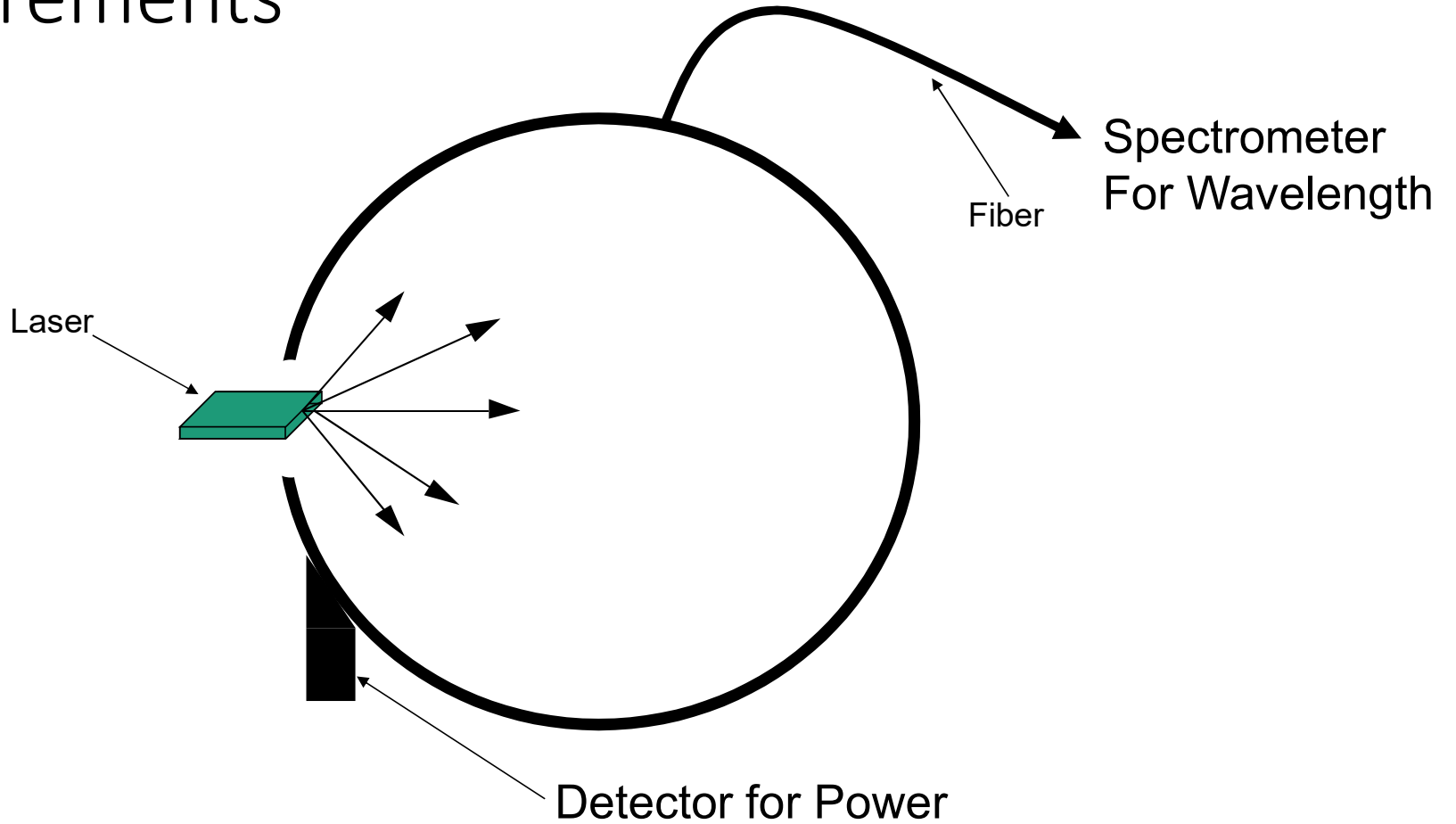
Protected Silver
0.3 to >12um

InfraGold
0.65 to >12um

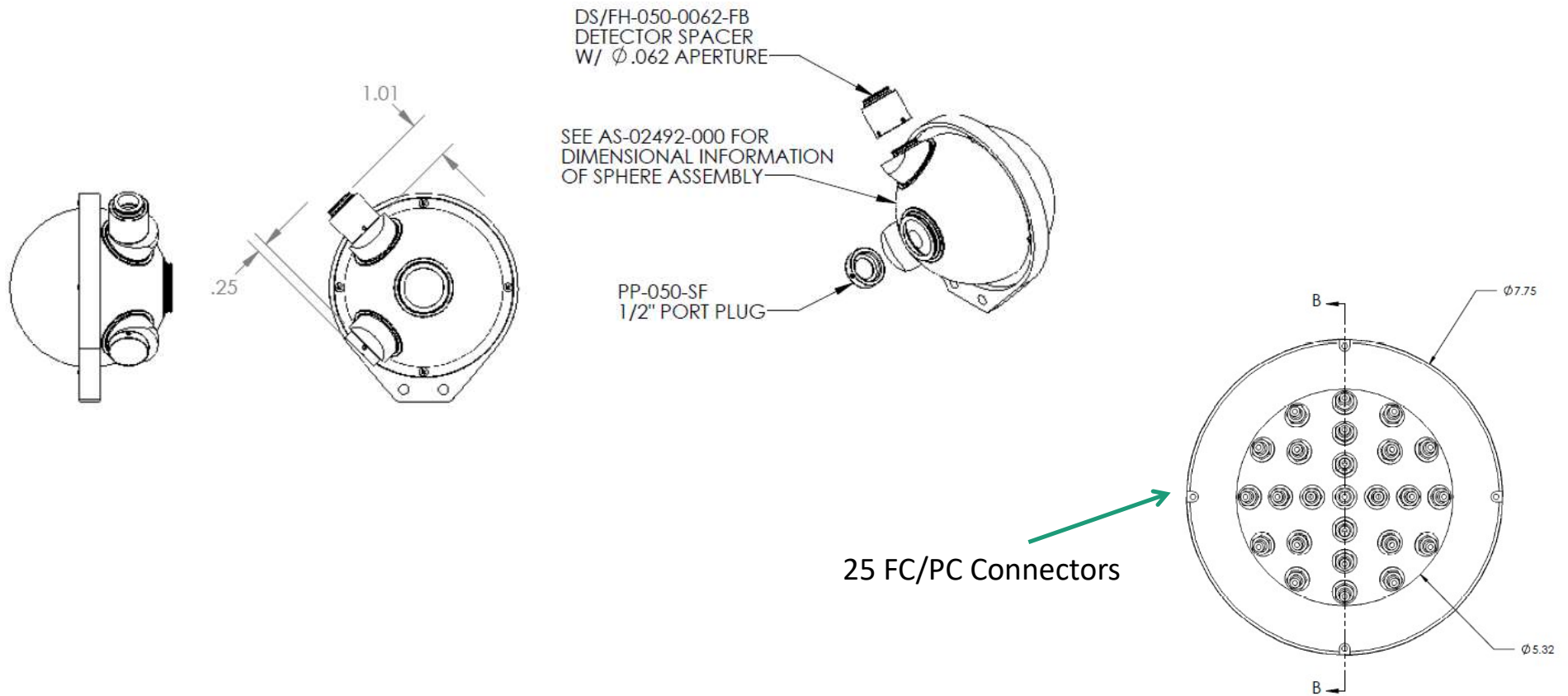
Diode Laser/Stack or Optical Fiber



Wavelength and Power – Simultaneous Measurements



Multiple detectors on a sphere (Si, IGA, etc)



Temporal Issues with Spheres

Spheres and Speckle (Coherence)

- Spheres DO NOT Remove Coherence (unless very large diam.)
 - Speckle patterns can be readily observed at the output of spheres
 - Can be a problem for fiber coupling where core size is close to the speckle size (speckle/no speckle spots).
- Speckle can be “defeated” in some applications by simply “dithering” the laser or sphere physically.
 - Causes the speckle pattern to move spatially and randomly
 - If the frequency of the physical movement is faster than the scan rate of the sampling device the spatial field is averaged and appears uniform.

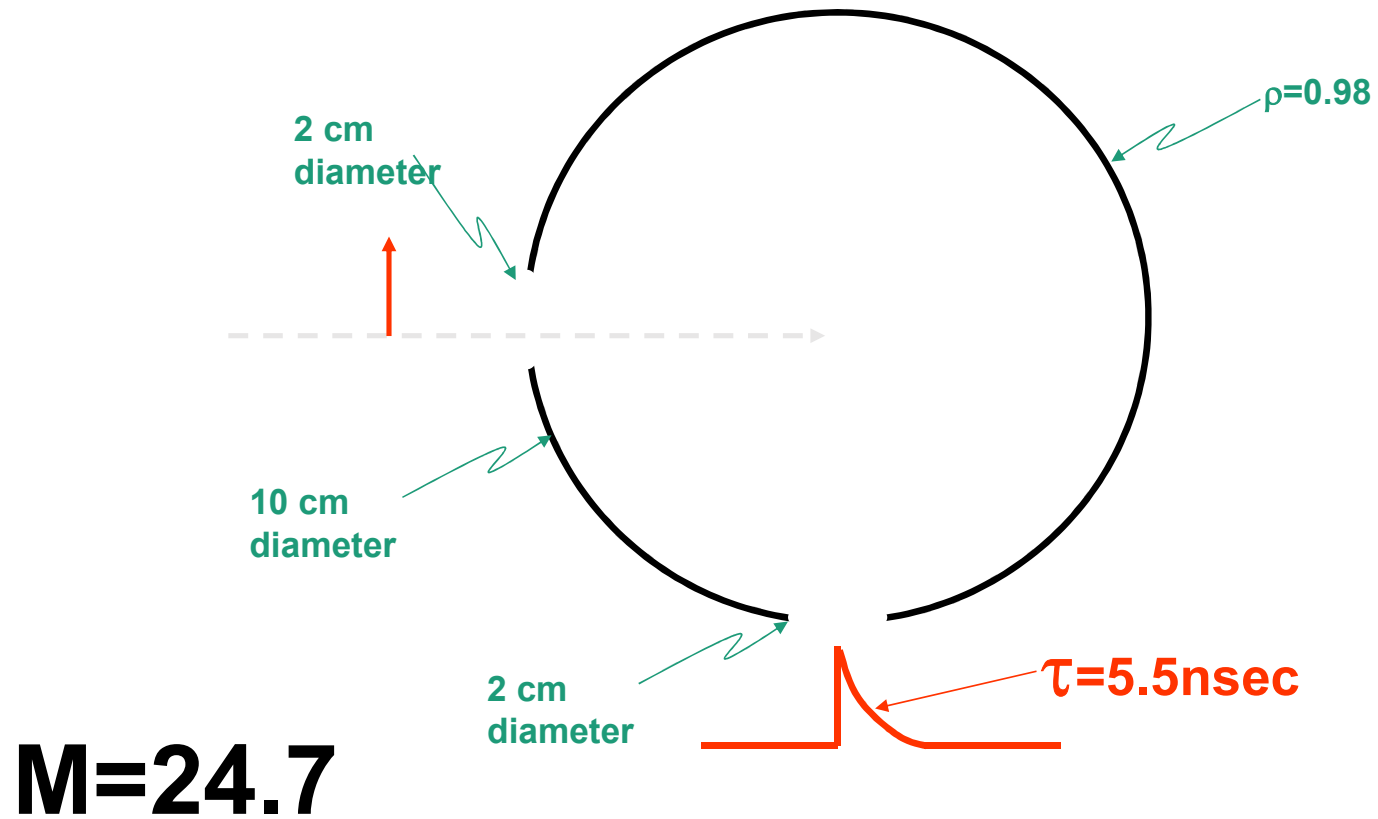
Sphere Time Constants

- Due to the multiple reflections in a sphere and the “random” path length of each photon, not all photons arrive at a designated point at the same time.
- A sphere acts very much like a “photon-capacitor” and has a time constant similar to this analogy.
- This Time Constant is driven by the D (diameter of the sphere), ρ_0 (the reflectance) and, c (the speed of light).

$$e^{-t/\tau} \quad \text{where} \quad \tau = -\frac{2}{3} \cdot \frac{D}{c} \cdot \frac{1}{\ln \rho_0}$$

- Typical time constants are 2-10ns.
- Problem can be a Solution in cases of very fast pulse where sphere time constant averages pulse

Sphere Time Constant Example



Sphere Advantages Summary

- Spatial
- Angular
- Robust, repeatable and easy measurement for most sources
- Use conventional detectors
- Wavelengths 0.1 μ m to >12 μ m (Sphere material dependant)
- Attenuation (SNR)
- Multipass chambers – path length = 10-30x Diameter.
- Polarization insensitive (removes polarization from inputs)
- Multiple Detectors can be employed
- Multiple Wavelengths at same time
- Real time detection (no thermal delay)
- Averaging of very fast pulses (time constant)
- Uniform coupling of light from one device to another (etendue)

Sphere Disadvantages Summary

- Throughput
- Time constants for high speed waveforms.
- SNR (Attenuation)
- Thermal limitations
- Multipass Chambers: Spheres are contamination sensitive (Humidity, Dust, Hydrocarbons, Air, etc)
 - Temporal stability depends on use
- Material Damage Thresholds
- Spectralon Sphere dimensions can change with temperature
- Uncertainty $\sim 1.5\text{-}2.5\%$ ($k=2$)
 - Si 450-850nm, InGaAs 1000-1700nm
- Uncertainty $\sim 3\text{-}6\%$ ($k=2$)
 - Si 300-450nm / 850-1050nm, InGaAs 900-1000nm / 1700-1800nm,
- Uncertainty Doesn't scale well with power $>1\text{W}$ due to calibration levels (10uW)
 - Opportunity to improve methods (here to learn)

Calibrating Spheres for Laser Power Measurements

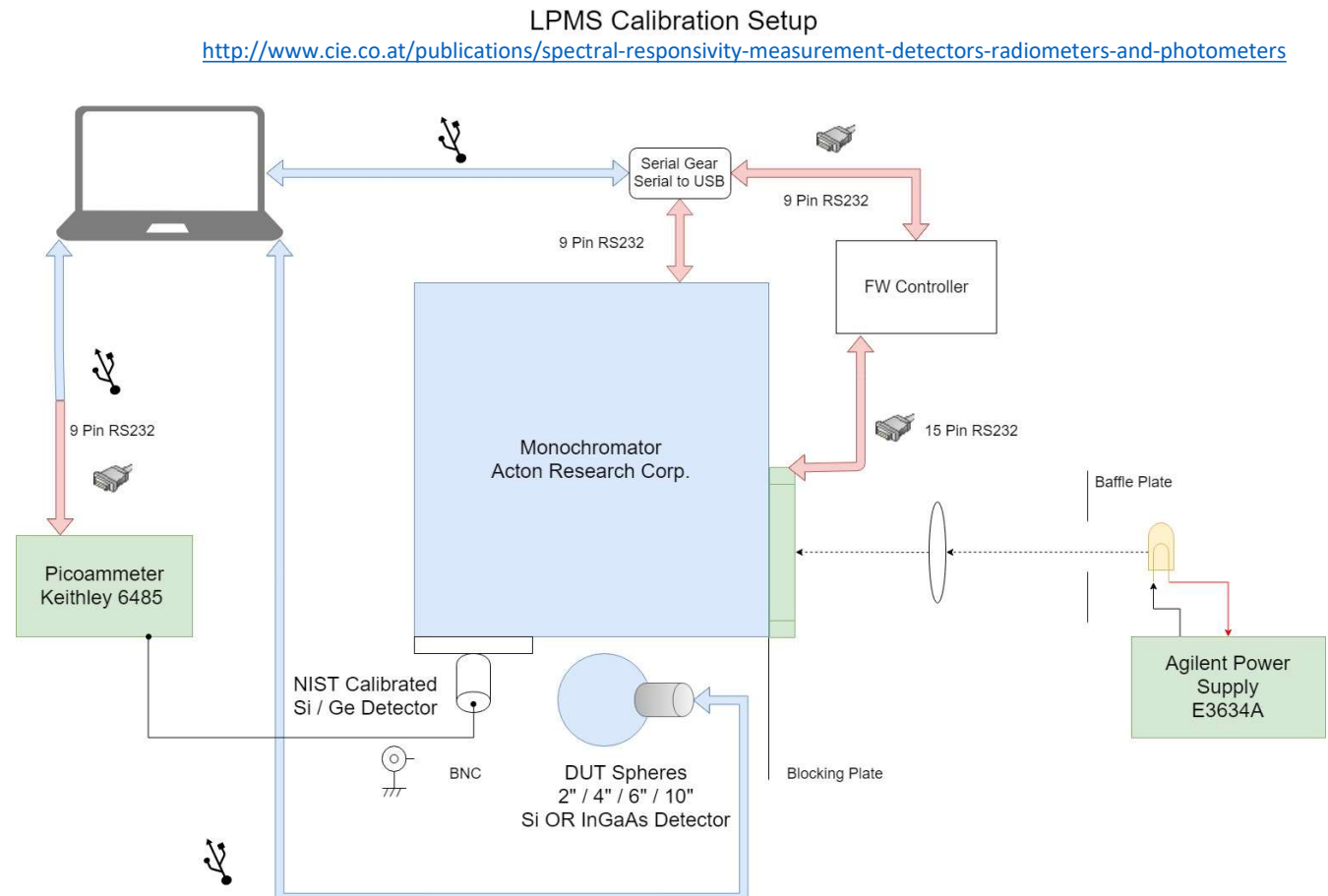
Calibration Setup - Based on CIE 220:2011

- Features

- Traceable to NIST
- Automated to do scans and create calibrations with selected reference detector traceable to NIST
- Creates Calibration Files readable by User Application

- Initial Setup

- Set:
 - Slit width at Entrance and Exit Ports
- Setup:
 - Reference Detector at Exit Port
- Prepare:
 - Mount DUT LPMS System on a suitable post for Exit Port



Process



Turn On and Stabilize

Light Source using Agilent Power Supply in Current Mode



Connect

Monochromator
Filter Wheel
Keithley6485
DUT LPMS Detector



Set

Averaging Period
Scans to Average



Select

NIST Detector
Calibration Type
Calibration Slot Settings
Calibration Wavelength Range and Interval



Start



Preview Calcs

Preview Calibrations



Write

Raw Data Files (.csv) For Uncertainty Calcs
Calibration File (.xml) For User Application

Applying Calibration Correction Multiplier

The power correction multiplier K_λ for the LPMS is defined as

$$K_\lambda = \frac{1}{R_{s\lambda}}$$

The radiant power ϕ_λ of the source is then calculated as:

$$\phi_\lambda = S_s K_\lambda$$

Where:

ϕ_λ = power of the of the laser, [W]

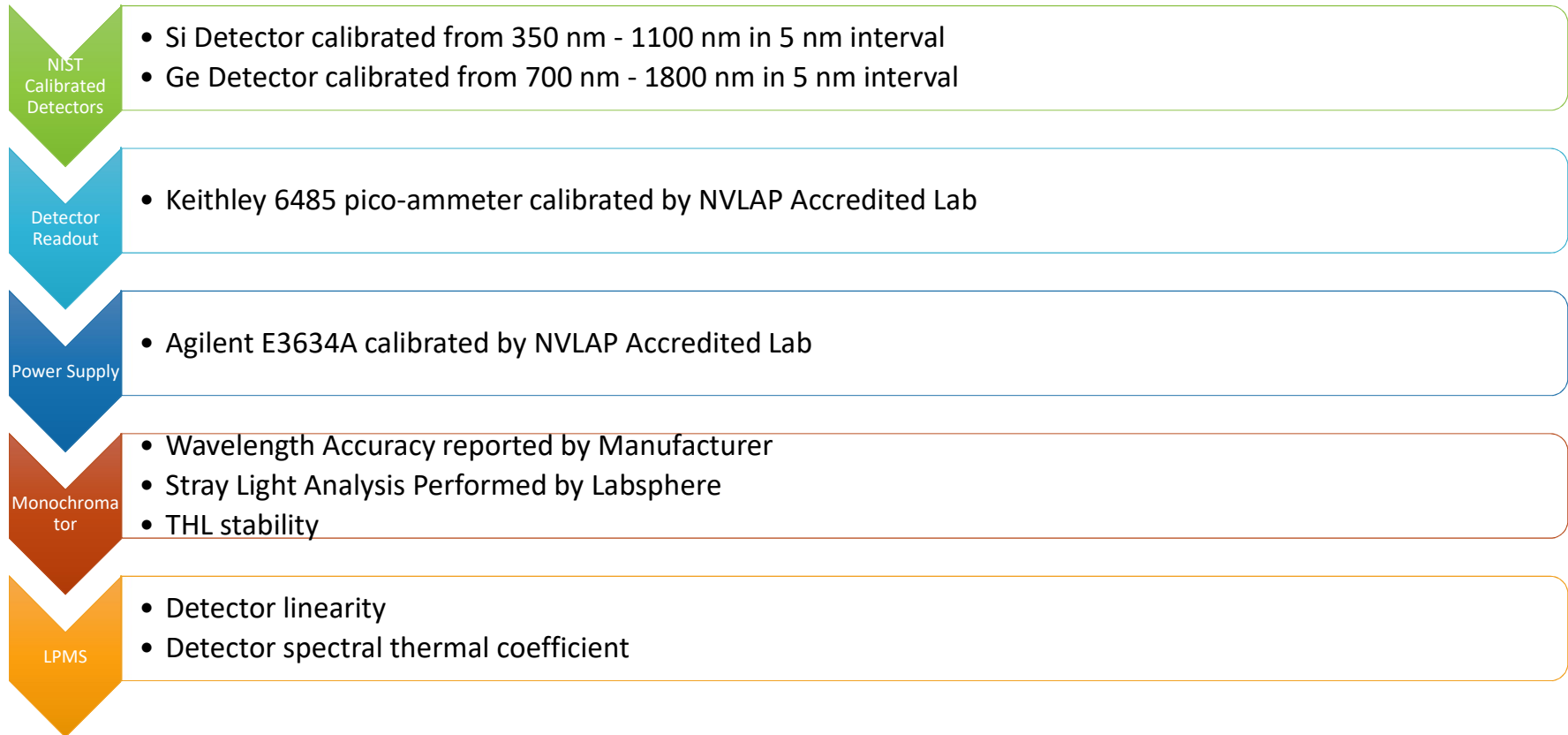
S_s = signal from the integrating sphere laser power meter, [A]

K_λ = power correction multiplier, [W/A]

Limitations

Wavelength Resolution	Lowest interval possible is 5 nm due to NIST Calibration
Time	Standard Calibration Wavelength Interval 10 nm As these are transient detectors, averaging is required, helps calibration and uncertainty evaluation If requested lower than 10 nm wavelength steps revisit calibration cost
Error	Silicon detector responsivity below 400 nm and above 1000 nm are low, measured power may have errors InGaAs detector responsivity below 800 nm and above 1650 nm are low, measured power may have errors
Measurement Uncertainty	Si detector NIST reported uncertainty below 400 nm and above 1000 nm are high, High Measurement Uncertainty Ge detector NIST reported uncertainty below 800 nm and above 1650 nm are high, High Measurement Uncertainty

Traceability



Uncertainty



Analysis Environment

NIST/NPL Validated Computation Procedure

Modular and Scalable Architecture



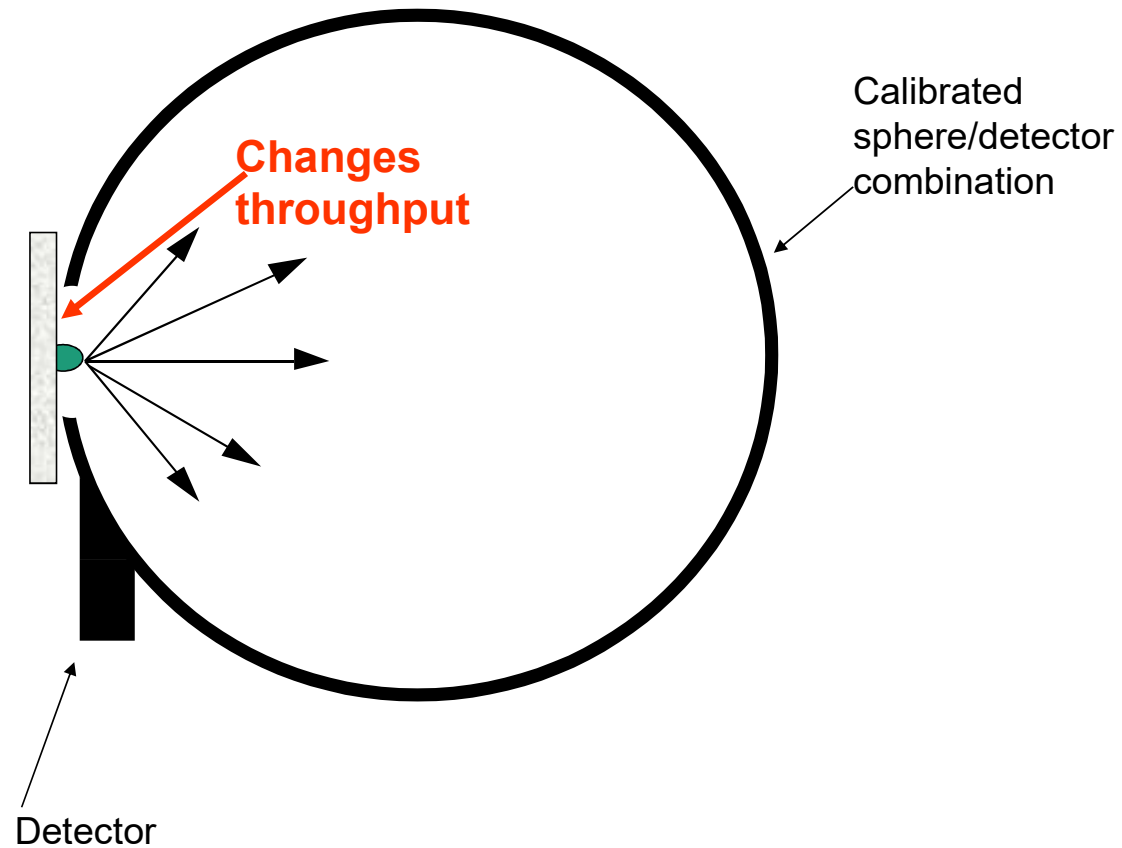
Expanded Uncertainty

Performed Pre-release analysis

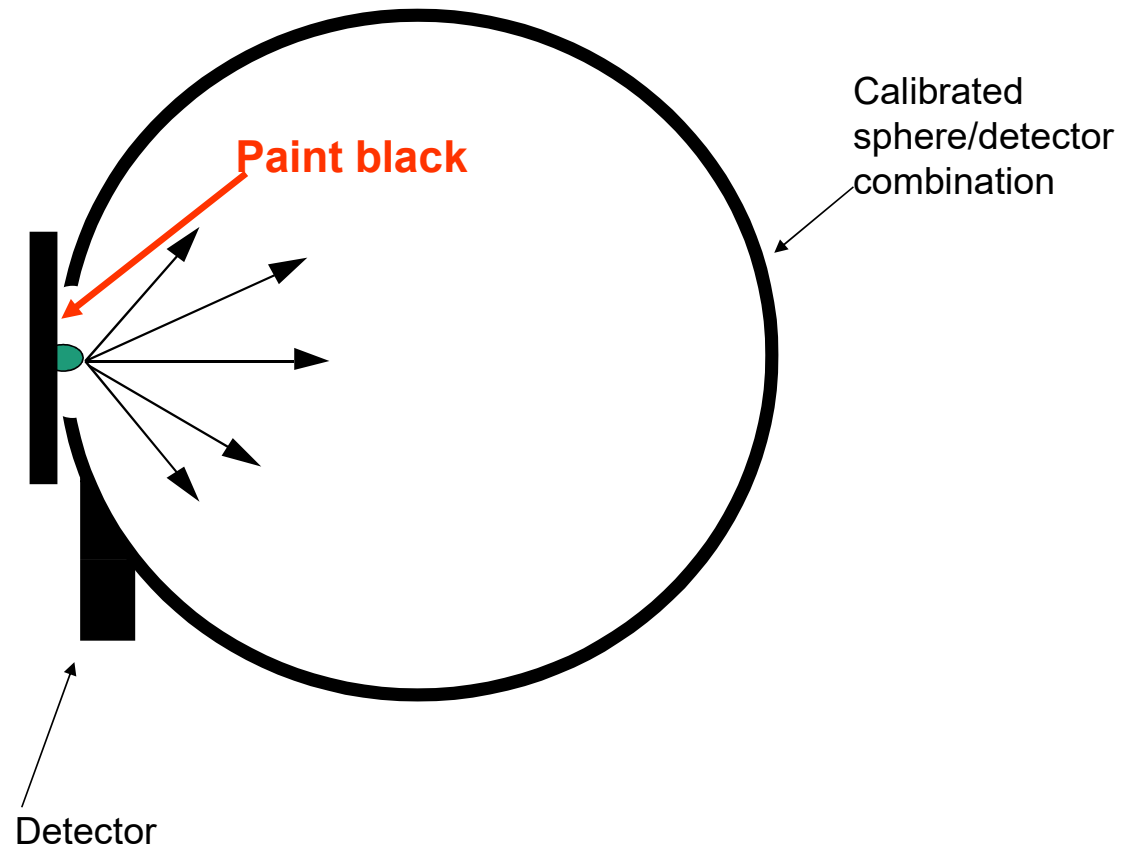
Can be reported with each calibrated unit

Substitution Correction for Sphere Calibrations

Substitution Error – Diode/LED

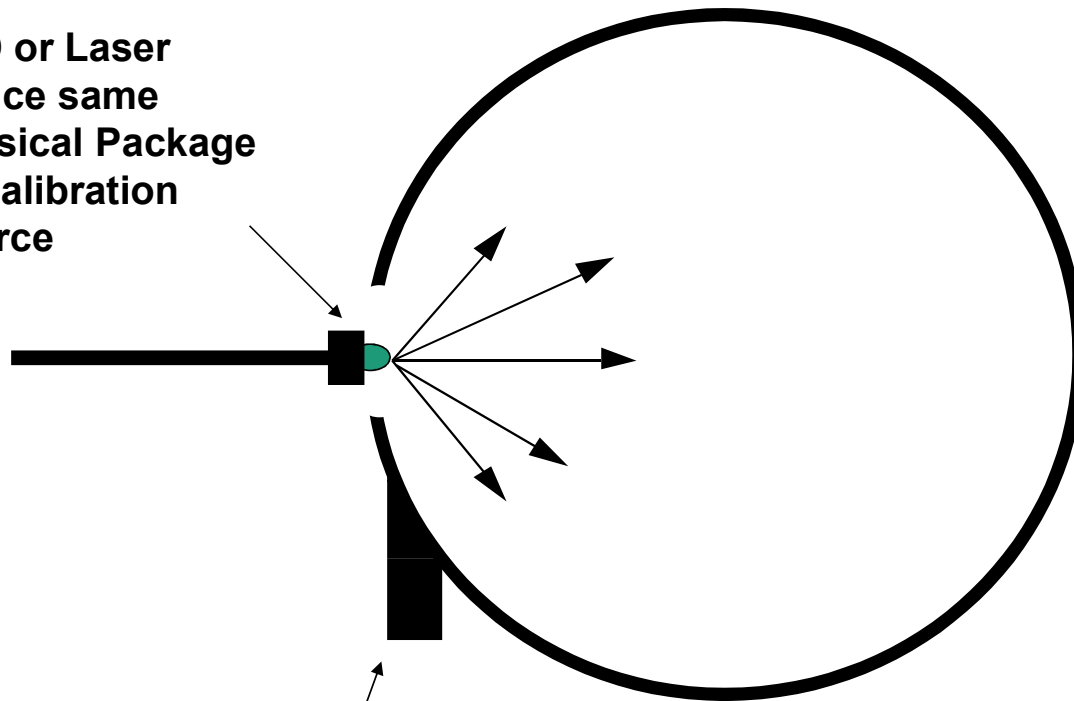


Substitution Error



Substitution Error – Use “Golden” Device

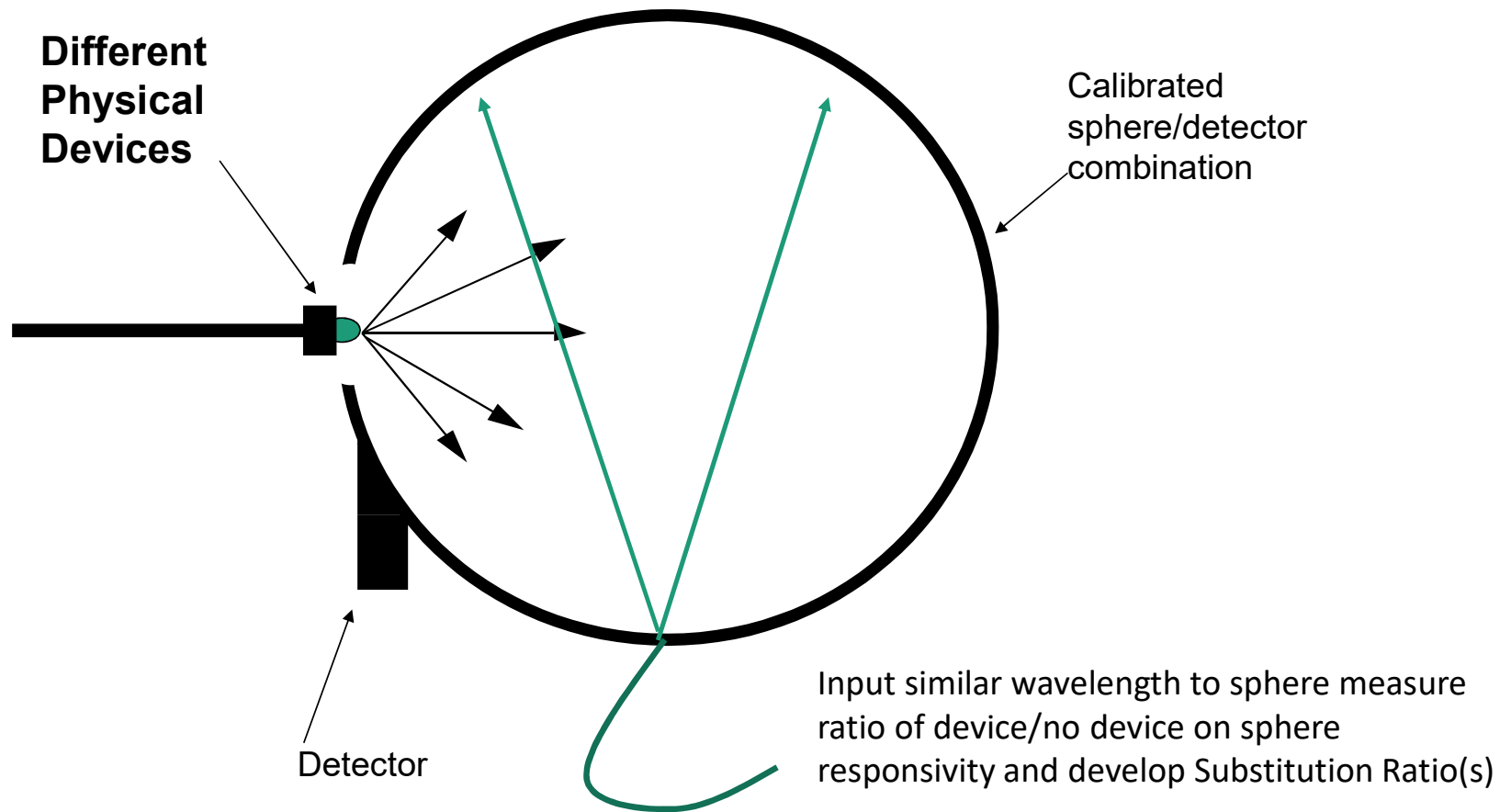
LED or Laser
device same
Physical Package
as calibration
source



Calibrated
sphere/detector
combination

Detector

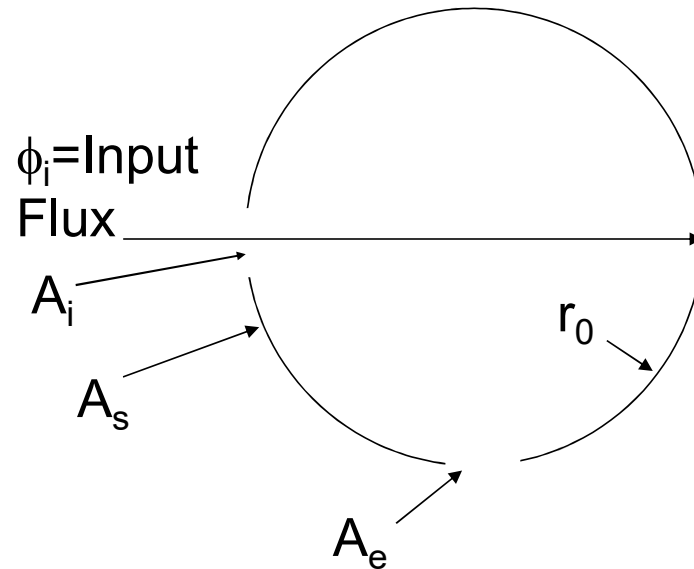
Substitution Error – Use Auxilliary Source



Sphere Throughputs with Various Devices

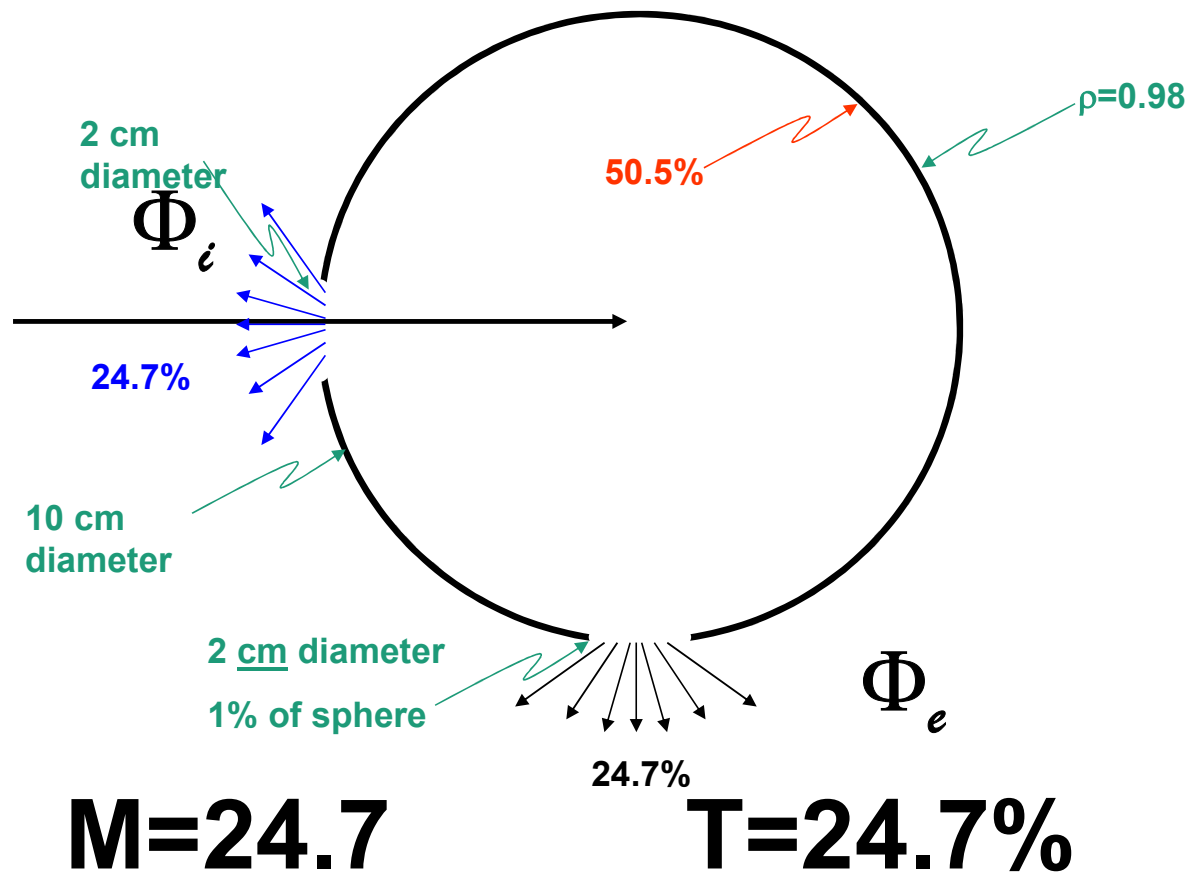
Throughput: Energy at a Port for a Sphere

- Energy at a port means we assume pi-steradian solid angle (drops pi from Sphere Radiance).
- Efficiency Calculation:
10cm sphere (98%)
w/(2) 2cm ports =
~24.7% at the exit port.



$$Flux = \phi_i * \left(\frac{A_e}{A_s} \right) * \frac{\rho_0}{1 - \rho_0(1 - f)}$$

So...Where Does the Energy Go?



Thoughtput Equation for a Detector

- Sphere Wall Radiance, $L = \frac{\phi_i}{\pi A_s} * \frac{\rho_0}{1 - \rho_0(1 - f)}$

- Throughput for Detector:

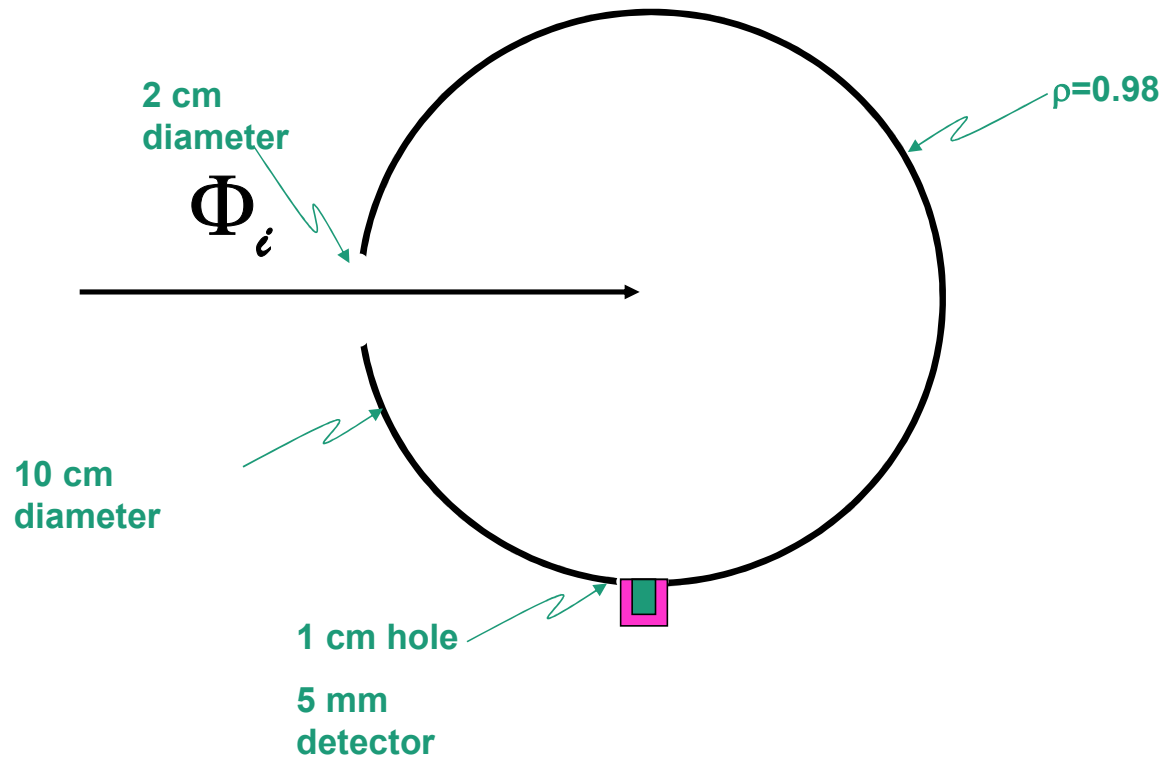
$$T_{Detector} = \phi_i * \frac{1}{\pi A_s} * \frac{\rho_0}{1 - \bar{\rho}} * A_d * \Omega$$

- $L * \text{Detector Area} * \text{Solid Angle}$

- Example: 0.5cm detector – 10cm Sphere

- -15-20dB (NA 1.0)

Sphere and Detector Throughput Example



$$M=30.4 \quad T=1.9\% \quad (-17.2\text{dB})$$

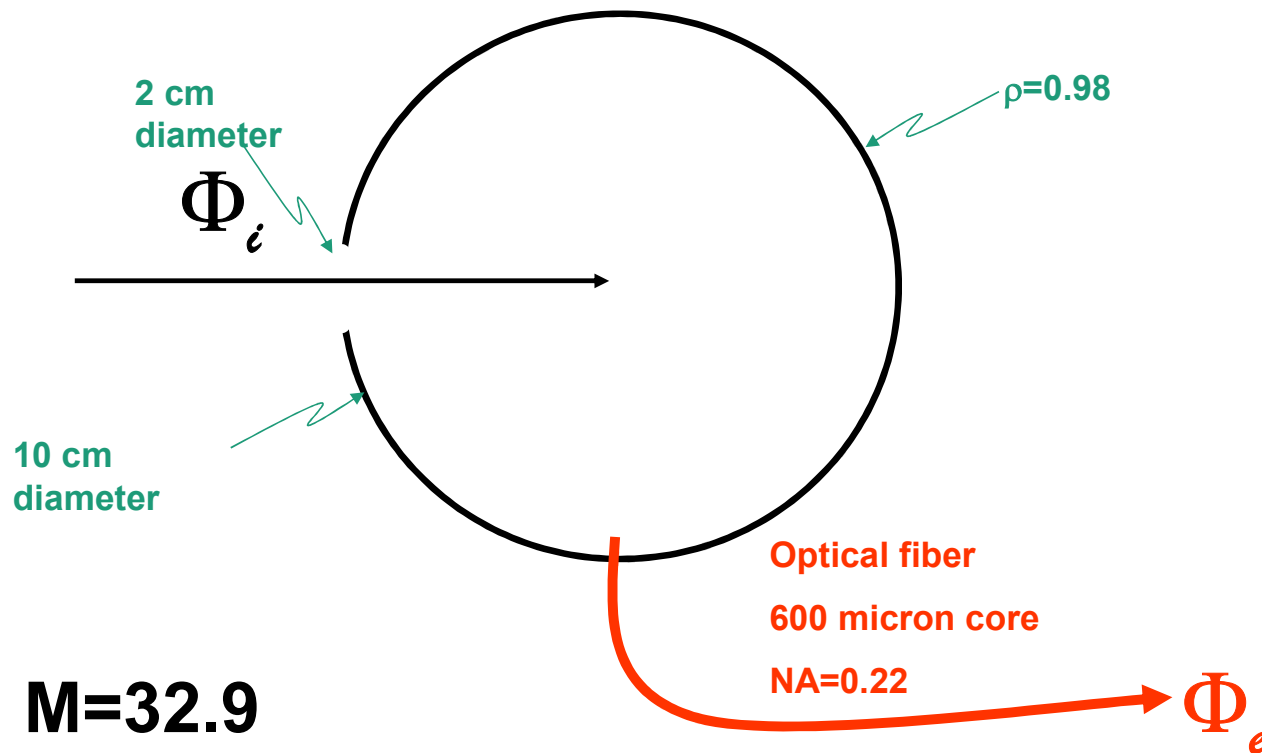
Throughput Equation for a Fiber

- Sphere Wall Radiance, $L = \frac{\phi_i}{\pi A_s} * \frac{\rho_0}{1 - \rho_0(1 - f)}$

- Throughput for Fiber:
$$T_{Detector} = \phi_i * \frac{1}{\pi A_s} * \frac{\rho_0}{1 - \bar{\rho}} * A_f * \Omega * (1 - r)$$

- $L * \text{Fiber Core Area} * \text{NA (Field of View)} * (1 - \text{Reflectance of Fiber Face})$
- Example: Telecom Fiber (10cm Sphere, 98%):
 - 9um Fiber/NA 0.2 = (>-95dB!)

Sphere and Fiber Throughput Example



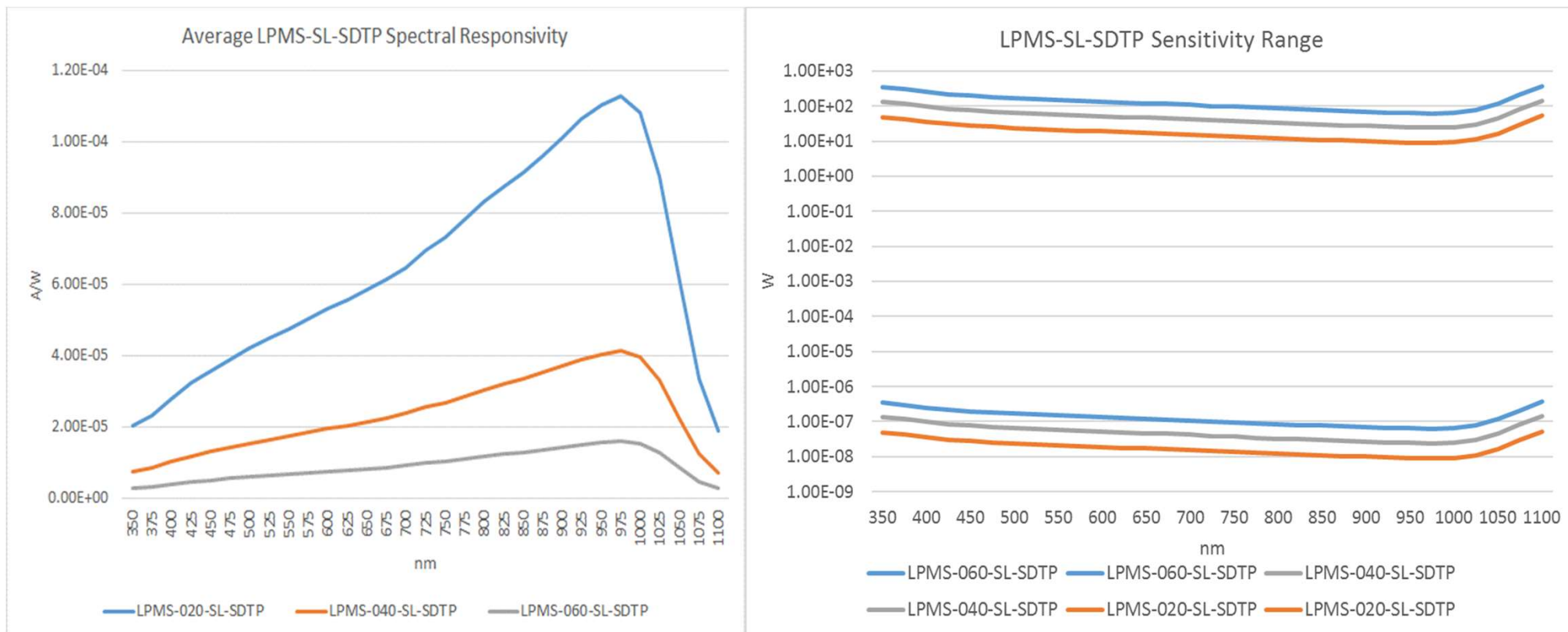
$$M=32.9$$

$$T=1.4 \times 10^{-5} = 0.0014\% = -48.5\text{dB}$$

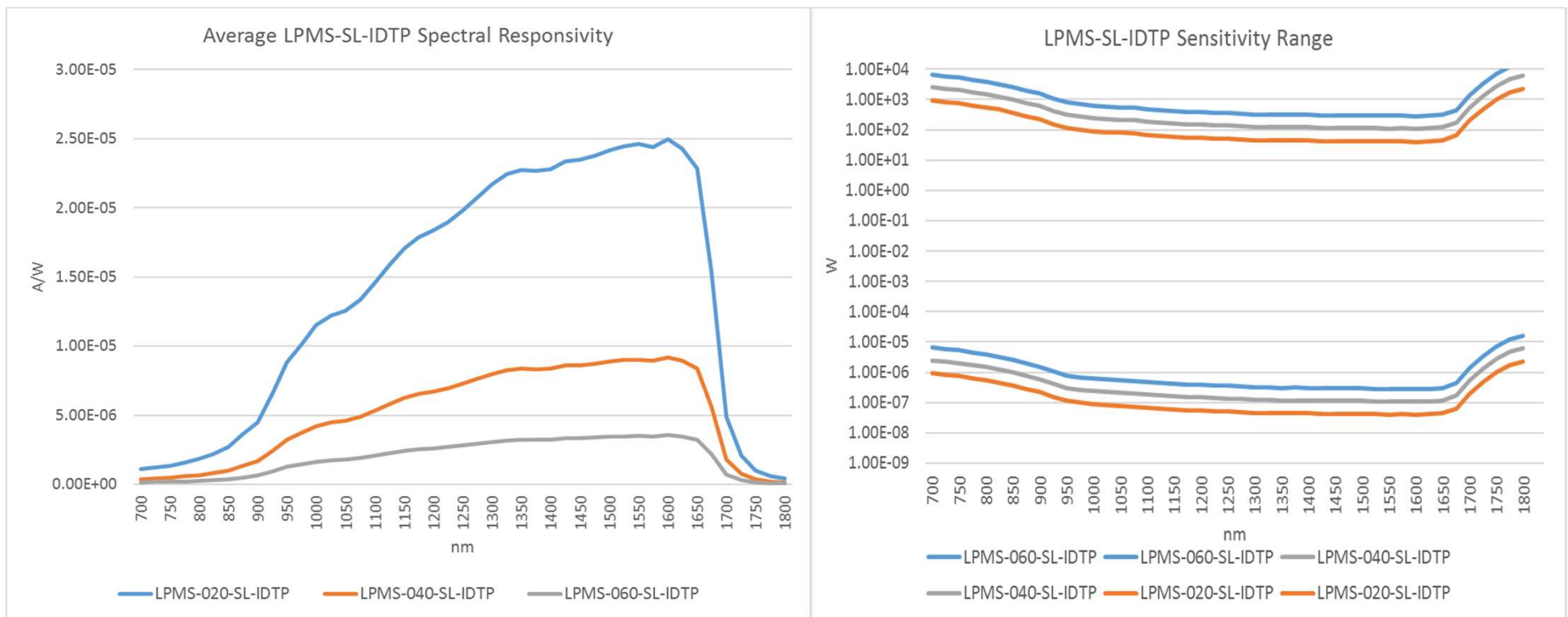
10cm Sphere Throughput - Detectors & Fibers

		dB to Detector								
		NA	0.018	0.126	0.178	0.399	0.691	1.000		
		Solid Ang.	0.001	0.05	0.1	0.5	1.5	3.142		
mm	Det. Active Area		sr	sr	sr	sr	sr	sr		
1	0.01 cm2		-67.73	-50.74	-47.73	-40.74	-35.97	-32.76	dB	
2	0.04 cm2		-61.71	-44.72	-41.71	-34.72	-29.95	-26.74	dB	
5	0.25 cm2		-53.75	-36.76	-33.75	-26.76	-21.99	-18.78	dB	
7.5	0.5625 cm2		-50.23	-33.24	-30.23	-23.24	-18.47	-15.26	dB	
10	1 cm2		-47.73	-30.74	-27.73	-20.74	-15.97	-12.76	dB	
25.4	2.25 cm2		-44.21	-27.22	-24.21	-17.22	-12.45	-9.24	dB	
		dB to Fiber								
		NA	0.12	0.2	0.3	0.4	0.6	1		
Refl Fiber	0.8 Sr		0.045	0.126	0.283	0.503	1.131	3.142		
um - diam	Fiber Area		sr	sr	sr	sr	sr	sr		
9	6.36E-07 cm2		-100.13	-95.69	-92.17	-89.67	-86.15	-81.71	dB	
12	1.13E-06 cm2		-97.63	-93.19	-89.67	-87.17	-83.65	-79.22	dB	
25	4.91E-06 cm2		-91.26	-86.82	-83.30	-80.80	-77.28	-72.84	dB	
100	7.85E-05 cm2		-79.22	-74.78	-71.26	-68.76	-65.24	-60.80	dB	
250	4.91E-04 cm2		-71.26	-66.82	-63.30	-60.80	-57.28	-52.84	dB	
1000	7.85E-03 cm2		-59.22	-54.78	-51.26	-48.76	-45.24	-40.80	dB	
5000	1.96E-01 cm2		-45.24	-40.80	-37.28	-34.78	-31.26	-26.82	dB	

Silicon on SL: Spectral & Dynamic Range



InGaAs on SL: Spectral & Dynamic Range



Laser Power Damage Thresholds for Spheres



Material	Max Temperature (°C)
Spectralon	400
Spectraflect	160
Permaflect	100
Infragold	n/a

Damage threshold is the ability of the sensors or surface to survive the energy from an impinging beam. This depends on many factors including, but not limited to: pulse width, wavelength, irradiated area, exposure time, and the ability of the material to dissipate the energy.

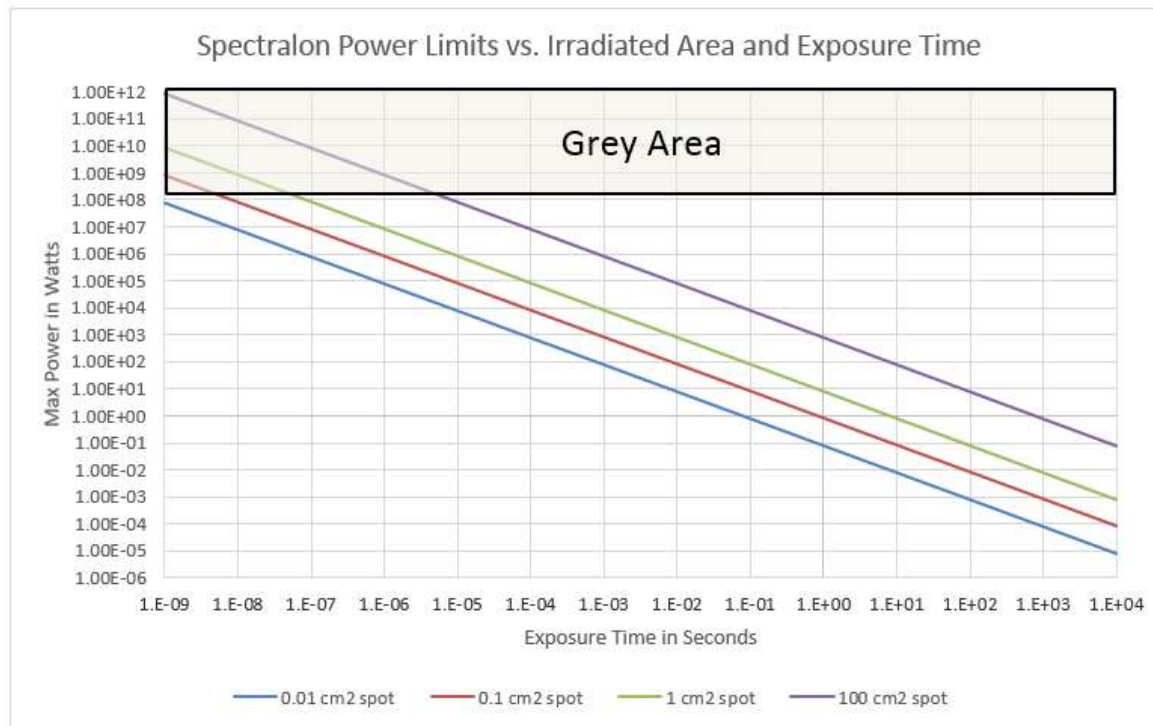


Laser
Damage
Threshold

Material	Laser Type	Laser Wavelength	Energy Density	Power Density	Source
Spectralon	Pulsed (20ns, 20Hz)	1064nm	4 J/cm ²	160 MW/cm ²	Montana Laser Optics, Inc.
Spectrafect	Q-Switched YAG	532nm	1.7 J/cm ²		Anecdotal
Spectrafect	Pulsed (20ns, 20Hz)	1064nm	0.7 J/cm ²	28 MW/cm ²	Big Sky Laser Technologies
Infragold	Pulsed (80ns, 20Hz)	10600nm	10.3 J/cm ²		Big Sky Laser Technologies
Infragold	[CO ₂]	10600nm	19.3 J/cm ²		Anecdotal

The typical laser damage threshold for some Labsphere optical materials is summarized above.

Laser Power Damage Thresholds



Graphical Example of Spectralon Sphere for quick reference

Thank You!

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PRODUCT SLIDES & SUPPORTING INFORMATION

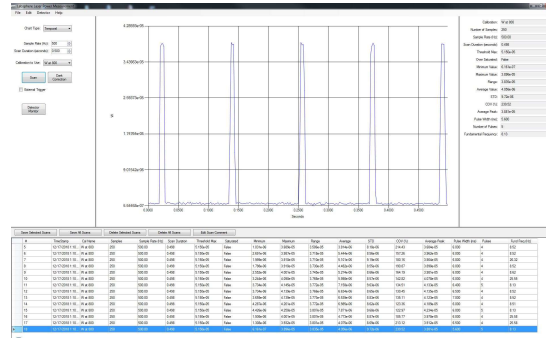
Solution



Detectors/Pre-Amp, Adaptor & Aperture



LPM Spheres



LPMS Software



LPMS Series

New Laser Power Systems



Pulsed Laser Power Measurement Systems

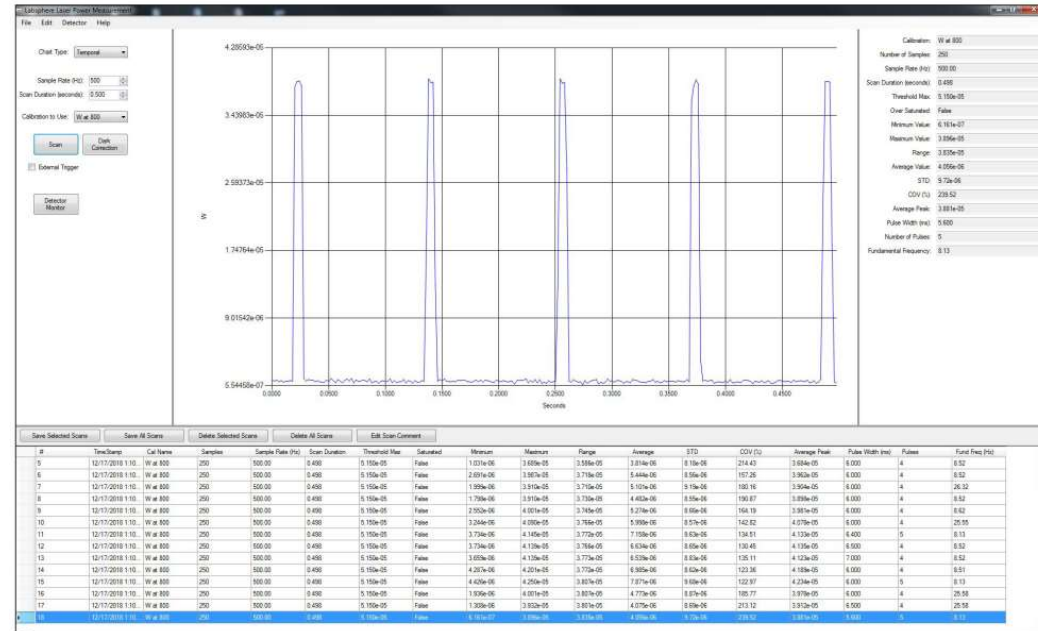
Accurate, reproducible method of determining total laser and laser diode power

<https://www.labsphere.com/site/assets/files/2610/pb-13031rev03lpmsystems.pdf>

Liquid Cooled High Power Systems



Example of Labsphere's Laser Power Measurement Software



Solutions Matrix

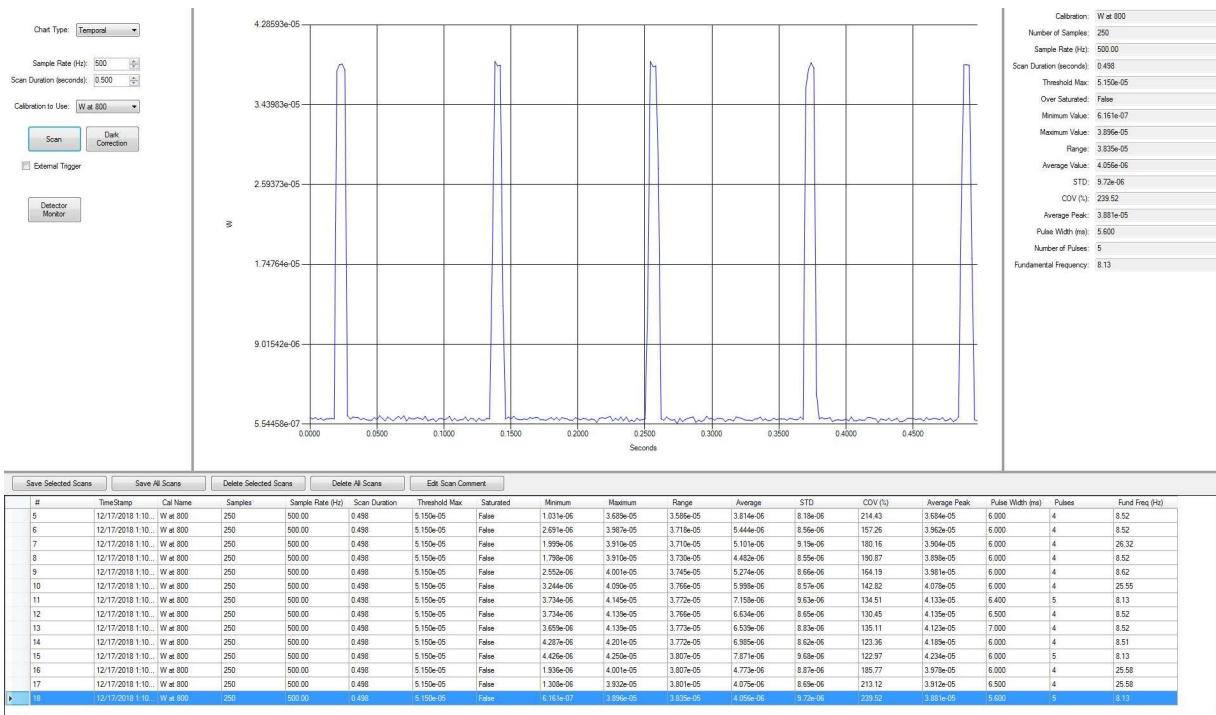
Sphere	Spectrafect		Spectralon		Infragold
Applications/Detector	Si	InGaAs	Si	InGaAs	InGaAs
Low power VIS NIR lasers	✓				
Mid-power lasers in VIS NIR, more robust			✓		
Low power NIR lasers		✓			
Mid-power lasers in NIR, more robust				✓	
High-power lasers in NIR, higher heat threshold, robust					✓

Differentiating Measured and Reported Values

- Average Radiant Power at n^{th} wavelength (CW)
- Average Peak Radiant Power at n^{th} wavelength (pulsed)
- COV (CW)
- Detector sampling rate, Hz
- Detector scan interval, sec
- Laser Power Density: the instantaneous laser beam power per unit area. W/cm^2 with option to beam area in cm^2 . Require input of beam area
- Max Power (CW)
- Min Power (CW)
- Overrange warning
- Peak Radiant Power (Pulsed)
- Pulse Width or interval of duration of a pulse
- Radiant power range (CW)
- Radiant Power. W
- Repetition Rate/frequency (Pulsed)
- Duty Cycle
- Standard deviation (CW)
- Threshold Max for given LPMS detector sensitivity range and system responsivity
- Threshold Min for given LMPS detector sensitivity range and system responsivity
- Total measurement time: not necessarily the same as the laser emission duration during the measurement, sec
- Total pulses.
- Wavelength (chosen by customer based on laser output and data table from calibration)

Specifications: (Mid Power VIS-NIR)

Part number:	LPMS-020-SL-SDTP	LPMS-040-SL-SDTP	LPMS-060-SL-SDTP
Sphere Material	Spectralon		
Sphere Diameter:	2-inch	3.3-inch	5.3-inch
Sphere Entrance Port Diameter (port frame)	0.5-inch	1.0 inch	1.0-inch
Sphere sensor Port (nominal)	2, 0.5-inch port frames		
Sensor:	Silicon		
Spectral Range (nm):	350 – 1100		
Spectral Peak (nm):	975	975	975
Spectral Responsivity (A/W):	9.7E-5 @975	3.6E-5 @975	5.0E-6 @975
Minimum Power at 940nm	W	W	W
Maximum Power at 940 nm	W	W	W
Monitor Rise time (s)	0.0005		
Sampling Rate	Low 10Hz, High: 5000Hz		
Date recording Rate	5kHz with internal sample rate of 20kHz		
Recording Interval	0.1 to 0.0002 sec		
Computer Interface:	USB;		
Power Requirements	USB		
Operating Temperature	20 ⁰ – 40 ⁰ C		



- Software Installation
- Calibration files location
- Making measurements
- Live demo of features
- Saving measurement
- Using Triggering function

Hardware/Software Demo

Peak Power in a Pulse

Peak power is the product of the energy in the pulse, Q , and the pulse width (interval duration in time)

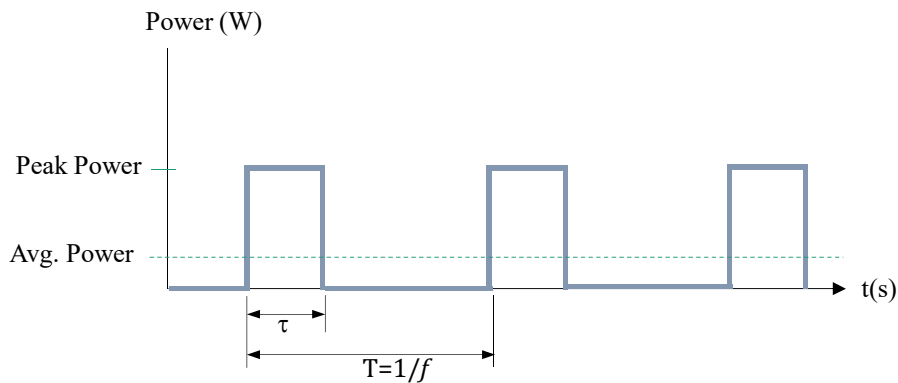
$$\phi_p = \frac{Q_\lambda}{\tau}$$

Average Peak power is calculated as the average of the power measurements within a pulse.

$$\bar{\phi}_{p\lambda} = \frac{\sum_i \phi_{p\lambda}}{n}$$

Average power in a pulsed laser

Consider a pulsed laser that has a constant power, ϕ_{peak} , over a pulse duration t , that repeats at a frequency f as shown below. The period of repetition is then $1/f$.



Average pulsed laser power :

$$\bar{\phi}_{pulse_{\lambda}} = \frac{1}{T} \int_0^T \phi(t) dt$$

Duty cycle, D :

$$D = \frac{\tau}{T}$$

Since there is no power after $t=\tau$, the integral above becomes:

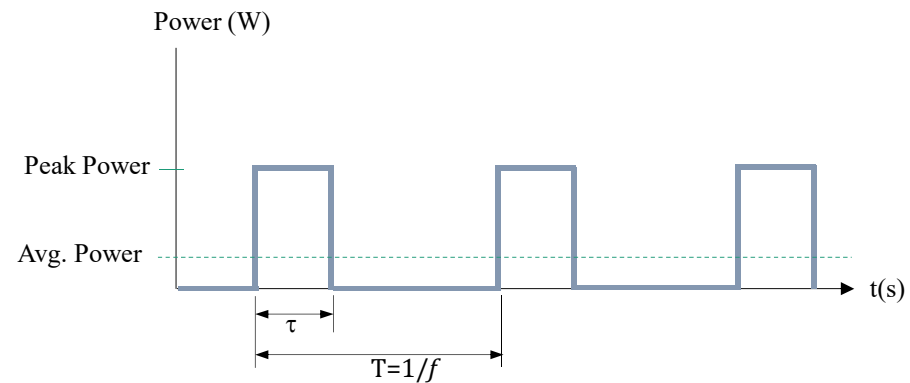
$$\bar{\phi}_{pulse_{\lambda}} = \frac{1}{T} \int_0^{\tau} \phi(t) dt = \frac{1}{T} \phi_{peak} \tau = D \phi_{peak}$$

The average pulse power is therefore equivalent to the average power over the course of one on/off cycle of the laser.

Peak Power from Average Peak Power

The peak power for a constant duty cycle and pulse width can be determined as:

$$\phi_{peak\lambda} = \phi_{Avg\lambda} \frac{T}{\tau}$$

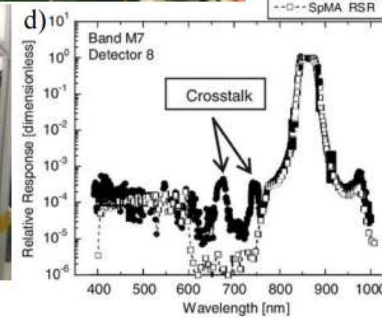
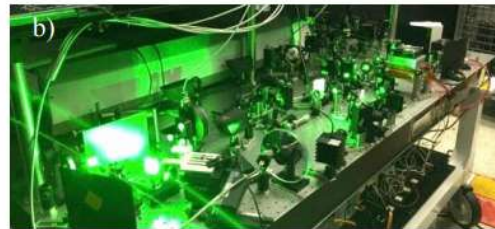
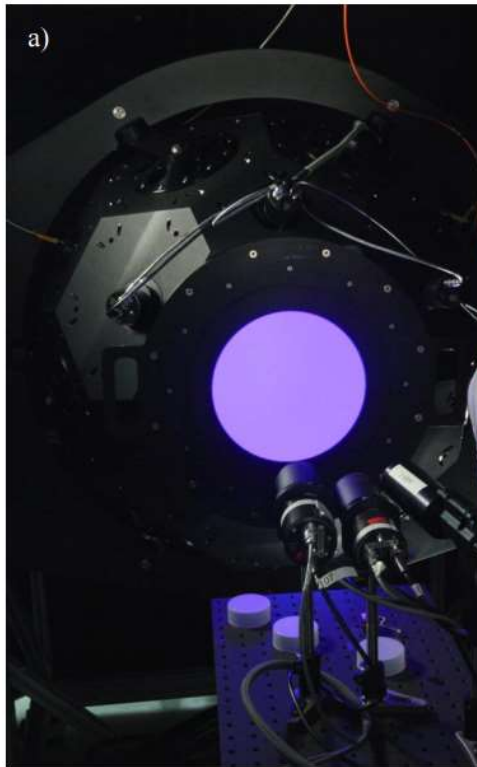


NASA GLAMR Primary Calibrator (<math><0.3\%</math> $k=2\sigma</math> Uncert.).$

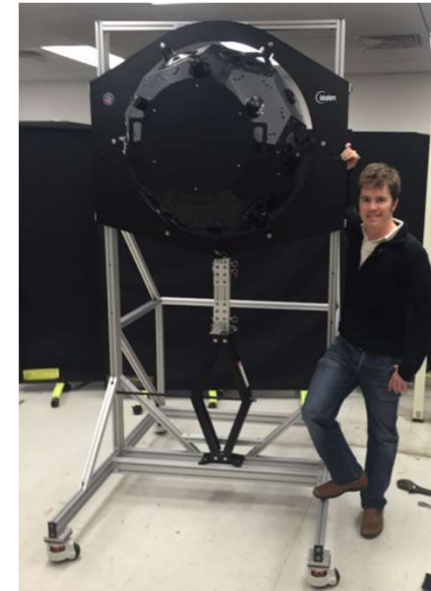


Goddard Laser for Absolute Measurement of Radiance (GLAMR)

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GLAMR is a tunable and high-powered laser system that provides an ideal light source for characterizing the spectral and radiometric response of an instrument. This pure signal allows decoupling of sensor features (e.g. linearity, crosstalk, scattered light) and orders of magnitude better absolute radiometric accuracies.



Geodesic Design with seams <math><0.5\text{mm}</math>

